

Search Notes

Application/Control No.

10/786,388

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

STRECK ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	746	11/7/2006	BT
438	747	11/7/2006	BT
438	756	11/7/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	11/7/2006	BT